

**Notice of References Cited**

Application/Control No.

10/670,968

Applicant(s)/Patent Under  
Reexamination  
WAMPLER ET AL.

Examiner

Maria N. Von Buhr

Art Unit

2125

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0171842 A1	09-2003	Teramoto et al.	700/182
*	B	US-2001/0012973 A1	08-2001	Wehrli et al.	700/193
*	C	US-6,847,922 B1	01-2005	Wampler, II, Charles W.	703/1
*	D	US-6,671,568 B2	12-2003	Gerken et al.	700/100
*	E	US-6,597,971 B2	07-2003	Kanno, Ichiro	700/245
*	F	US-6,505,092 B1	01-2003	Fukaya et al.	700/184
*	G	US-6,438,445 B1	08-2002	Yoshida et al.	700/173
*	H	US-5,991,528 A	11-1999	Taylor et al.	703/6
*	I	US-5,751,584 A	05-1998	Yuasa et al.	700/178
*	J	US-5,416,715 A	05-1995	Kinoshita et al.	700/178
*	K	US-5,136,903 A	08-1992	Hibi, Akira	82/1.11
*	L	US-4,651,601 A	03-1987	Sasaki, Takao	83/13
*	M	US-4,633,409 A	12-1986	Sekikawa, Katsuhide	700/183

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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